

# Finite output resistance in saturation

# Quick review

The equation used to define  $i_D$  depends on relationship between  $v_{DS}$  and  $v_{OV}$ :

- When  $v_{DS} \ll v_{OV}$  (i.e., the small  $v_{DS}$  model)

$$i_D = \left[ (\mu_n C_{ox} \left( \frac{W}{L} \right) v_{OV}) \right] v_{DS} \quad (1)$$

- When  $v_{DS} < v_{OV}$  (i.e., the large  $v_{DS}$  model)

$$\begin{aligned} I_D &= \mu_n C_{ox} \left( \frac{W}{L} \right) \left[ V_{OV} - \frac{1}{2} v_{DS} \right] v_{DS} \\ &= k'_n \left( \frac{W}{L} \right) \left[ V_{OV} - \frac{1}{2} v_{DS} \right] v_{DS} \end{aligned} \quad (2)$$

- When  $v_{DS} \geq v_{OV}$  (channel pinch-off and current saturation)

$$i_D = \frac{1}{2} k'_n \left( \frac{W}{L} \right) \quad (3)$$

- But what would happen when  $v_{DS} \gg v_{OV}$ ?

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# Finite output resistance in saturation

- In previous lectures, we assume (in saturation)  $i_D$  is independent of  $v_{DS}$ .
- Therefore, a change in  $v_{DS}$  has no effect on  $i_D$ .
  - This implies that the incremental resistance  $R_o$  is infinite
  - It is based on the idealization that, once the n-channel is pinched off, changes in  $v_{DS}$  will have no effect on  $i_D$ .
  - The problem is that, in practice, this is not completely true.
- In reality, the drift current increases, and  $i_D$  increases with increasing  $v_{DS}$

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# Finite Output Resistance in Saturation

What effect does increasing  $v_{DS}$  has on the n-channel once pinch-off has occurred?

- It will cause the pinch-off point to move slightly away from the drain and **create new depletion region**.
- Voltage across the (now shorter) channel will remain at  $v_{OV}$ .
- However, the additional voltage applied at  $v_{DS}$  will be seen across the **“new” depletion region**.

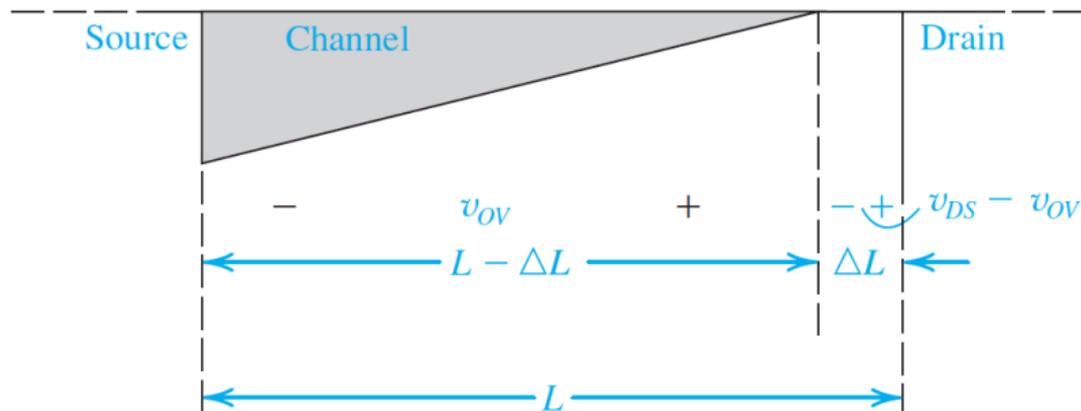
# Finite Output Resistance in Saturation

What effect will increased  $v_{DS}$  has on n-channel once pinch-off has occurred?

- This voltage accelerates electrons as they reach the drain end, and sweep them across the “new” depletion region.
- However, at the same time, the length of the n-channel will decrease. This is known as channel length modulation.

# Finite output resistance in saturation

- When  $v_{DS} > V_{OV}^2$ , the depletion region around the drain region grows in size.
- With depletion-layer widening, the channel length is in effect reduced, from  $L$  to  $L - \Delta L$ , a phenomenon known as **channel-length modulation**.

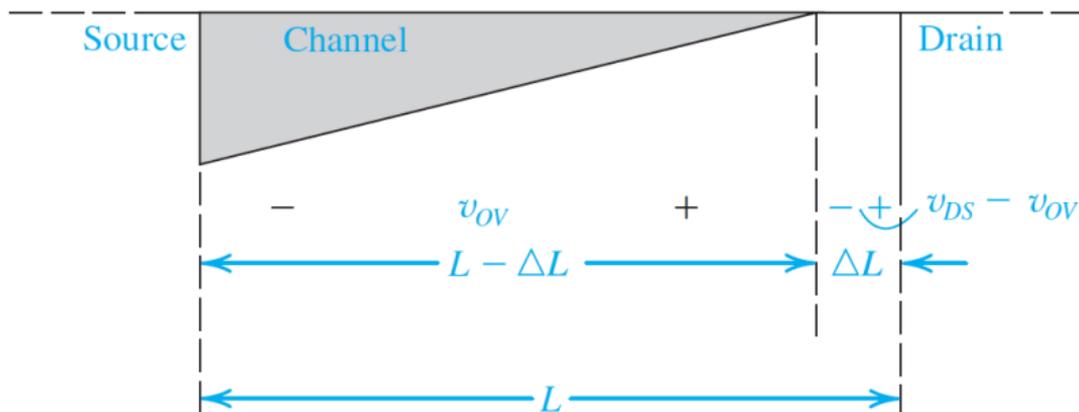


**FIG 1. Early Effect—Finite Output Resistance**

increasing  $v_{DS}$  beyond  $v_{DSsat}$  causes the channel pinch-off point to move slightly away from the drain; thus, reducing the effective channel length by  $\Delta L$

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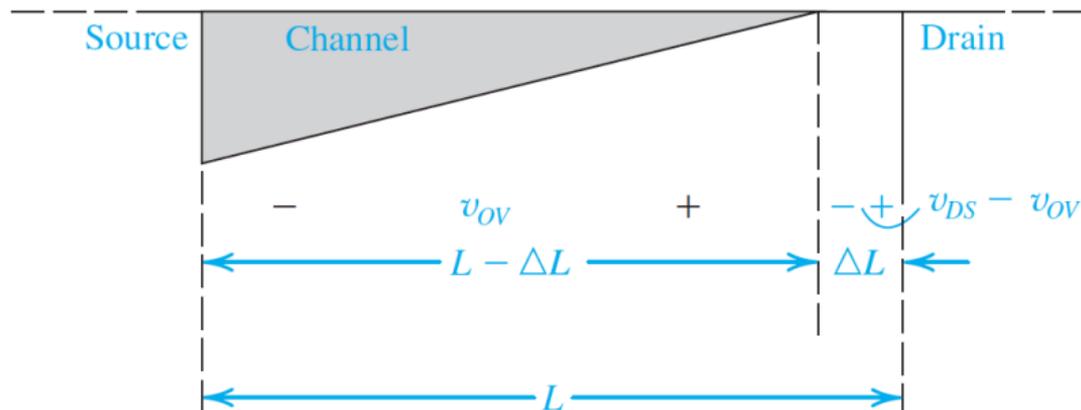


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# Finite output resistance in saturation

- As the channel length becomes shorter, the electric field, which is proportional to  $v_{DS}/L$ , becomes larger.
- Since  $i_D$  is inversely proportional to the channel length,  $i_D$  increases with  $v_{DS}$ .



**FIG 2. Early Effect—Finite Output Resistance**

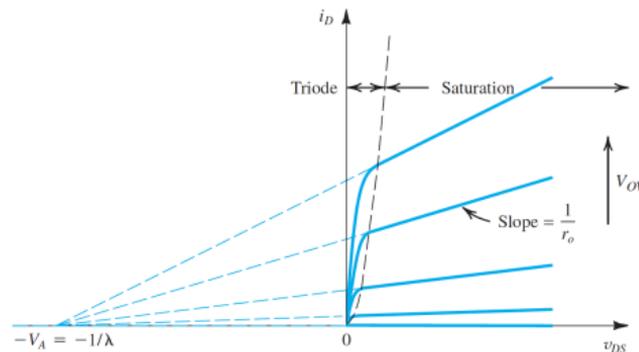
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- In reality, the drift current increases, and  $i_D$  increases with increasing  $v_{DS}$

$$i_D = \frac{1}{2}k'_n \left( \frac{W}{L} \right) (v_{GS} - V_{tn})^2 (1 + \lambda v_{DS}) \quad (4)$$

- $\lambda$  is a device parameter with the units of  $V^{-1}$ , the value of which depends on manufacturer's design and manufacturing process.  $\lambda$  is much larger for newer tech's
- The value of  $\lambda$  depends both on the process technology used to fabricate the device and on the channel length  $L$ .
- In short, we can draw a straight line between  $V_A$  and saturation.



**FIG 3. Early Effect—Finite Output Resistance**

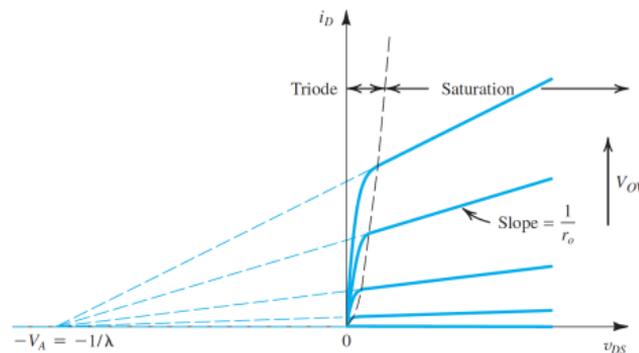
Effect of  $v_{DS}$  on  $i_D$  in the saturation region. The MOSFET parameter  $V_A$  depends on the process technology and, for a given process, is proportional to the channel length  $L$ .

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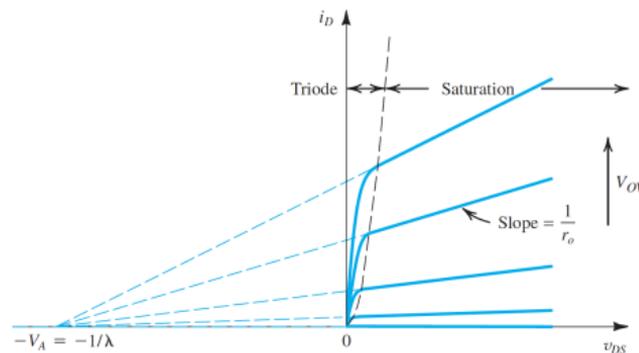
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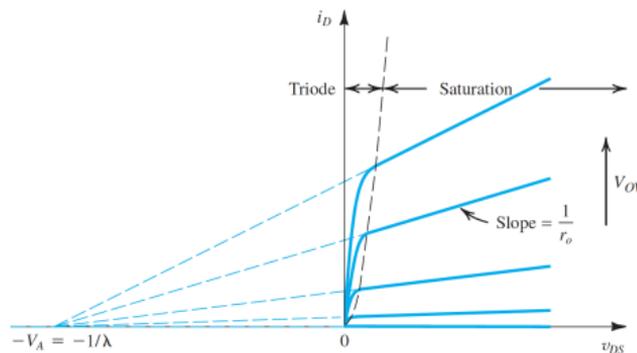
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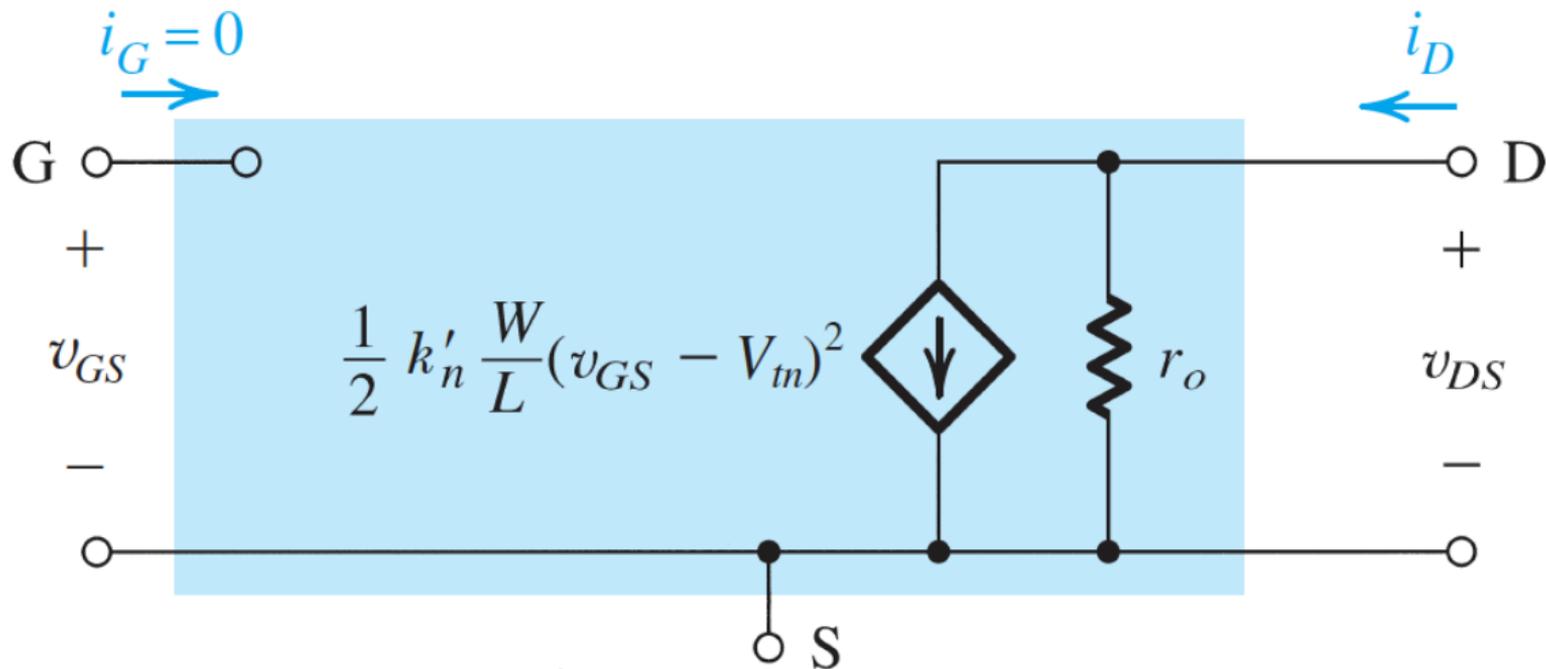
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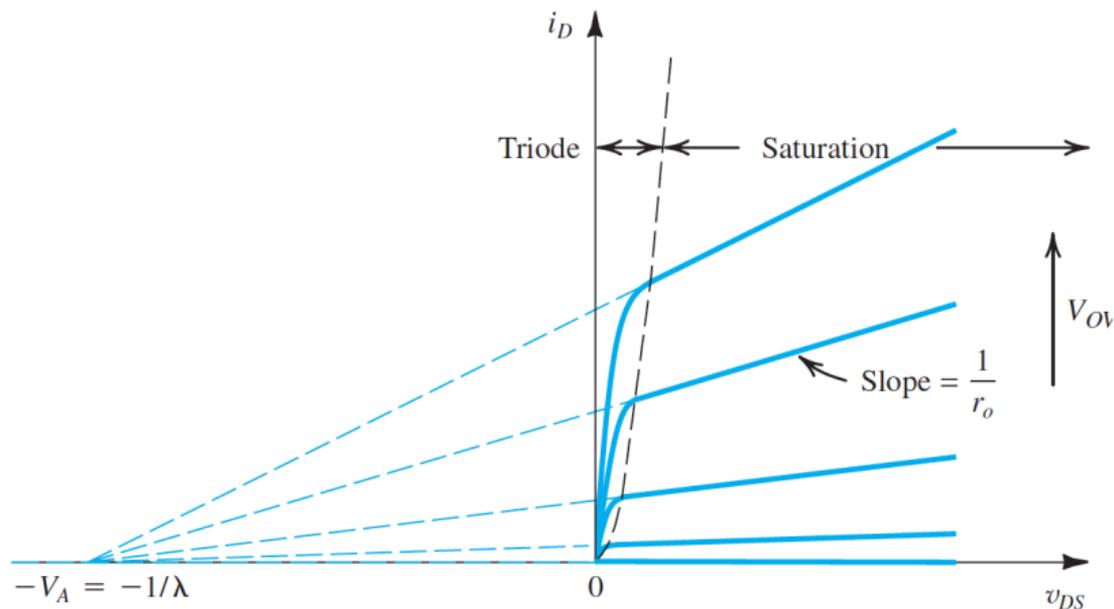
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**FIG 4.** Large-Signal Equivalent Model of the n-channel MOSFET in saturation, incorporating the output resistance  $r_o$ . The output resistance models the linear dependence of  $i_D$  on  $v_{DS}$  and is given by **Equation (4)**. Please note the addition of finite output resistance  $r_o$ .

# Defining the output resistance

Note that  $r_o$  is the  $1/\text{slope}$  of  $i_D$  vs  $v_{DS}$  curve



**FIG 5. Early Effect—Finite Output Resistance**

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$$r_o \equiv \left[ \frac{\partial i_D}{\partial v_{DS}} \right]^{-1} \quad (5)$$

- Combining Equation (4) and Equation (5), we have

$$\begin{aligned} \frac{\partial i_D}{\partial v_{DS}} &= \frac{\partial}{\partial v_{DS}} \frac{1}{2} k'_n \left( \frac{W}{L} \right) (v_{GS} - V_{tn})^2 (1 + \lambda v_{DS}) \\ &= \frac{1}{2} \mu_n C_{ox} \frac{W}{L} v_{ov}^2 \lambda \end{aligned} \quad (6)$$

- Thus, the output resistor is defined as shown in Equation (7)

$$\begin{aligned} r_o &= \left[ \lambda \frac{k'_n}{2} \frac{W}{L} (V_{GS} - V_{tn})^2 \right]^{-1} \\ &= \frac{1}{\lambda i_D} \\ &= \frac{V_A}{i_D} \end{aligned} \quad (7)$$

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